

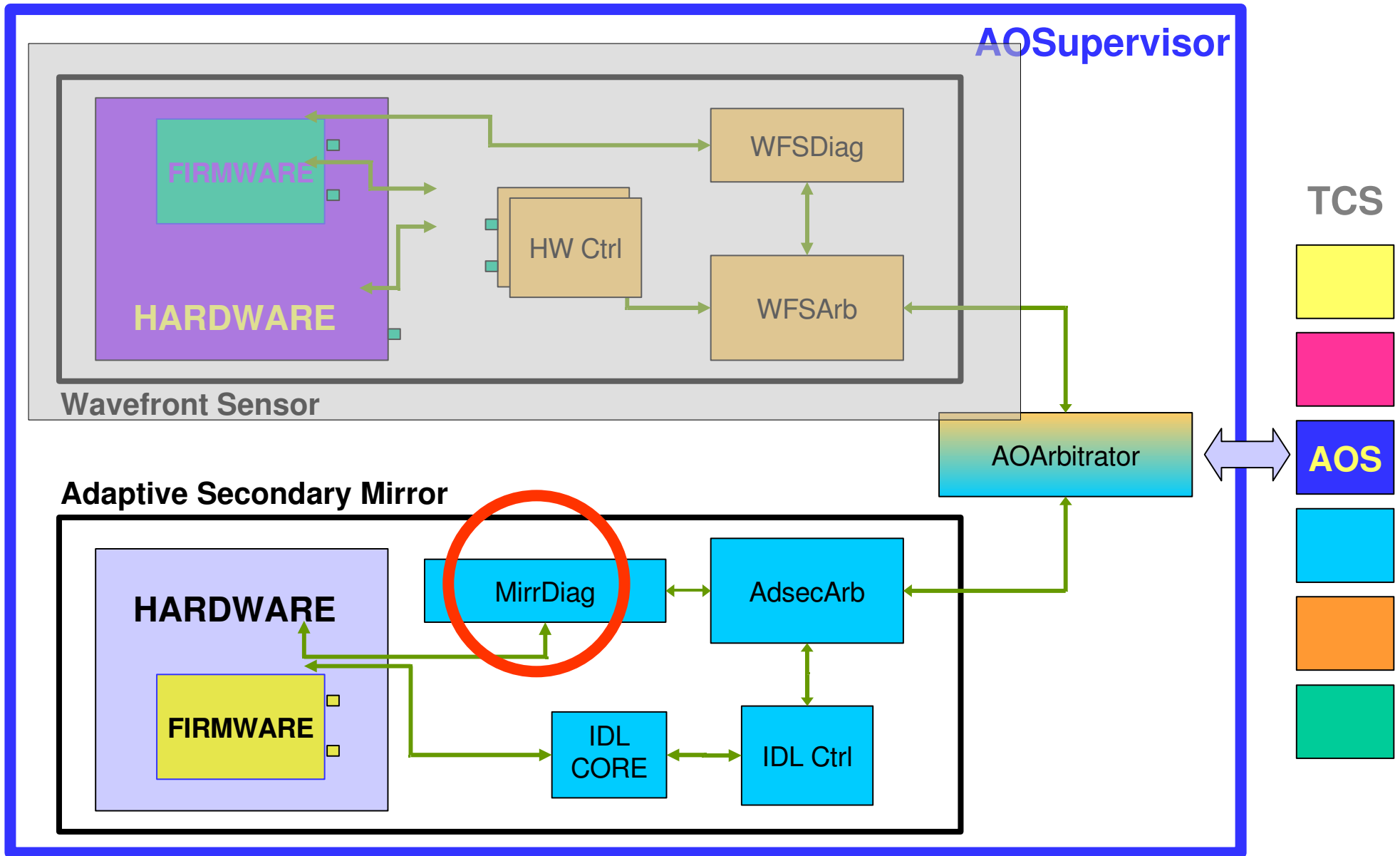
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# *LBT Adaptive Secondary Diagnostic Software*

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# Where?



# Target

- We want to keep under control all those parameters that can suggest the **onset of a safety risk** both for the electronics devices and for the glass shell.
- We want to **promptly react** when a dangerous situation is detected.
- We can use the diagnostic parameters provided by the control loop electronics to work out an on-line analysis of the **quality of the AO loop**.

# Where do risks come from?

- Bad commands sent by the wave-front sensor.
- Dust grains between the thin shell and the reference plate can induce stresses above a critical threshold.
- Hardware malfunctioning (e.g. of capacitive sensors or DACs) can result in the application of arbitrary high forces to the shell.

## Risks do not come from:

Not from turbulence: during “normal” functioning, shell shape corrections are not big enough to break the shell.

# Diagnostic sensors and raw data

## *Slow*

- Health status of electronics: boards **temperatures**, **power supply currents** and voltages, **coils currents**, etc...
- Periodically written on the on board memory and downloaded to the Supervisor.

## *RealTime*

- Control loop parameters: **distances** measured by capacitive sensors, **forces** applied by coils, **wave-front modal amplitudes** measured by WFS, etc...
- Written at full rate (up to 1kHz) on the on-board SDRAM memory. Downloaded to the Supervisor through Gbit ethernet.

# What can we monitor?

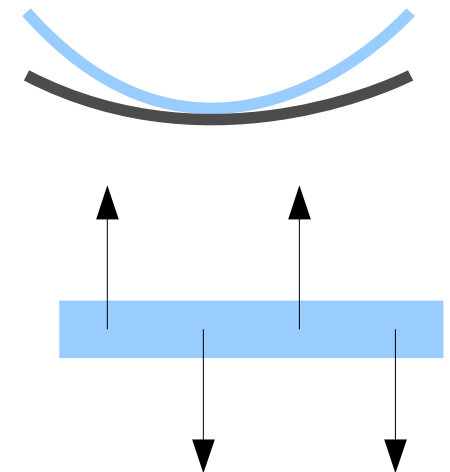
Obviously applied forces to prevent saturation of current drivers and shell position to prevent falling of the shell (!! ) and other direct quantities.

**Shell stress**: from Finite Element Analysis and actuator positions we compute the stress pattern in the shell.

**Correction residual**: difference between the shape required by the wave-front sensor and the measured figure.

**Forces distribution** on the shell to prevent a checkerboard pattern of the applied forces

**More coming soon .....**



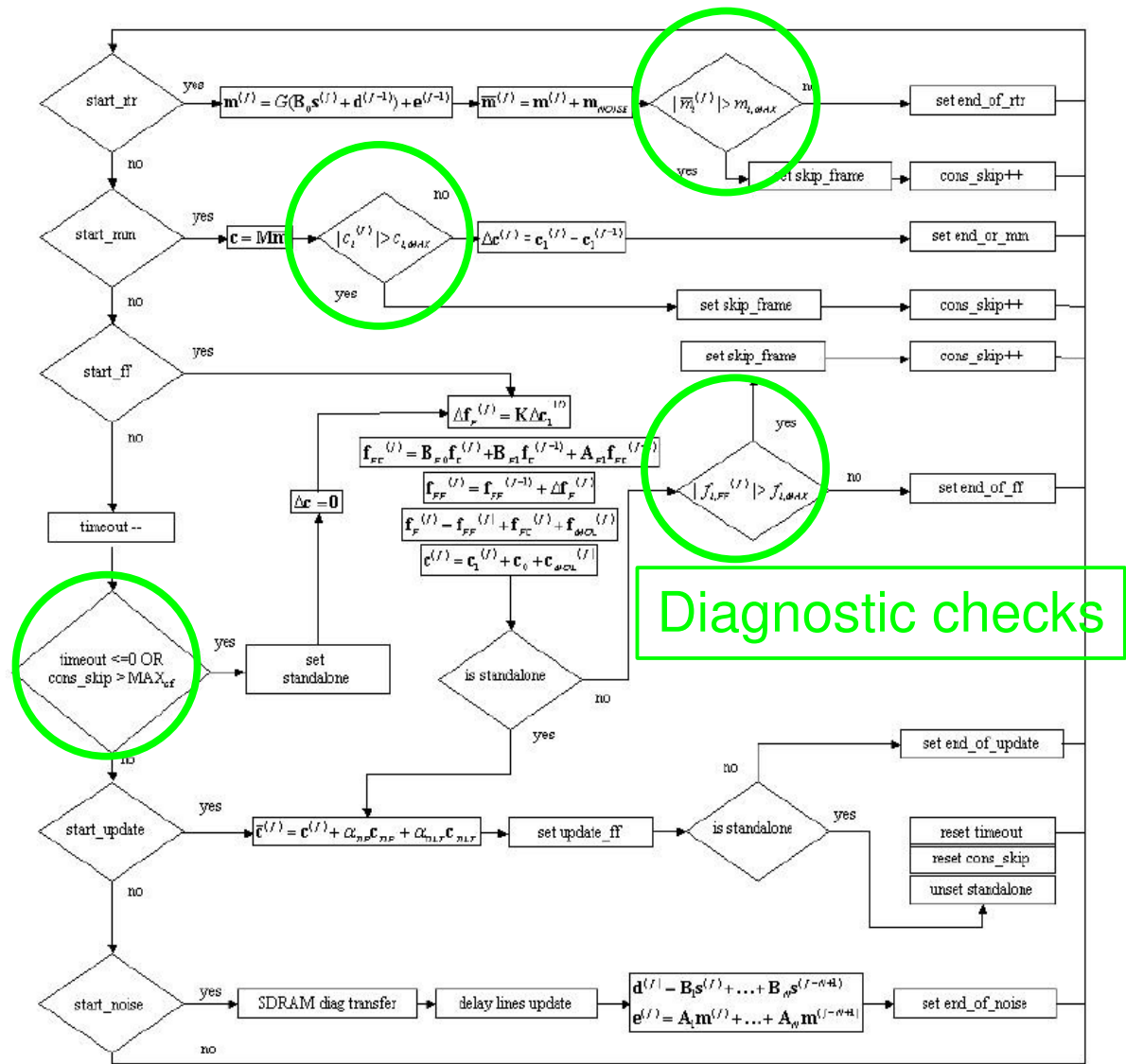
# On board real-time diagnostic

A real-time diagnostic is implemented in the DSP code used for the control loop. We can discard those frames that would result in too much high forces or stresses.

**Pro: real-time.** The “bad” frame is discarded without being applied.

**Con: Limited memory and power on DSP. No temporal history.**

DSP code is developed by Microgate

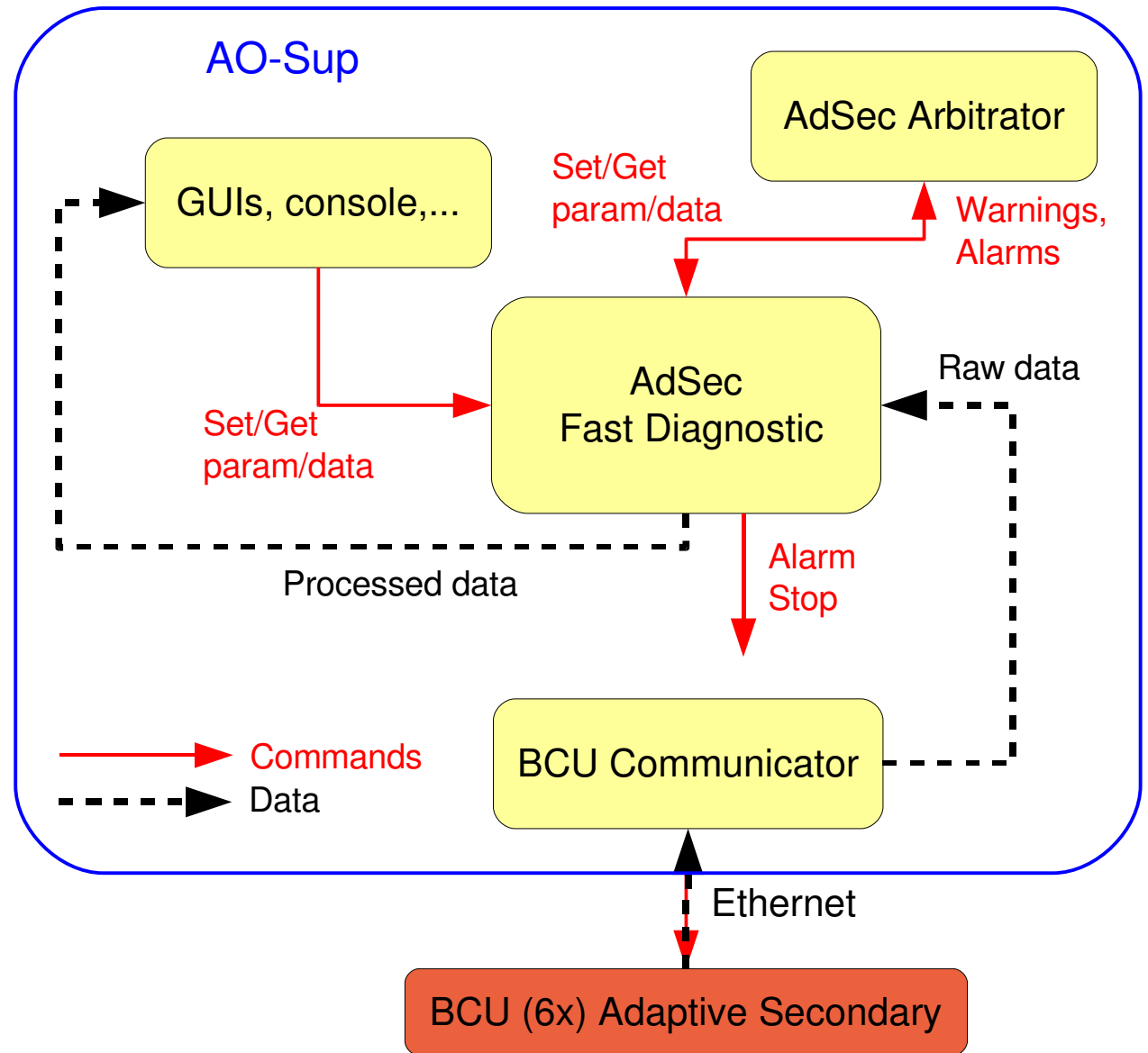


# On-line analysis of diagnostic data

DSP code can't trap every dangerous situations before applying commands.

Need a "fast" software that analyzes **a posteriori** the diagnostic data, detects the onset of pathological conditions and reacts.

The delay of such an analysis must be  $< \sim 10\text{ms}$ .





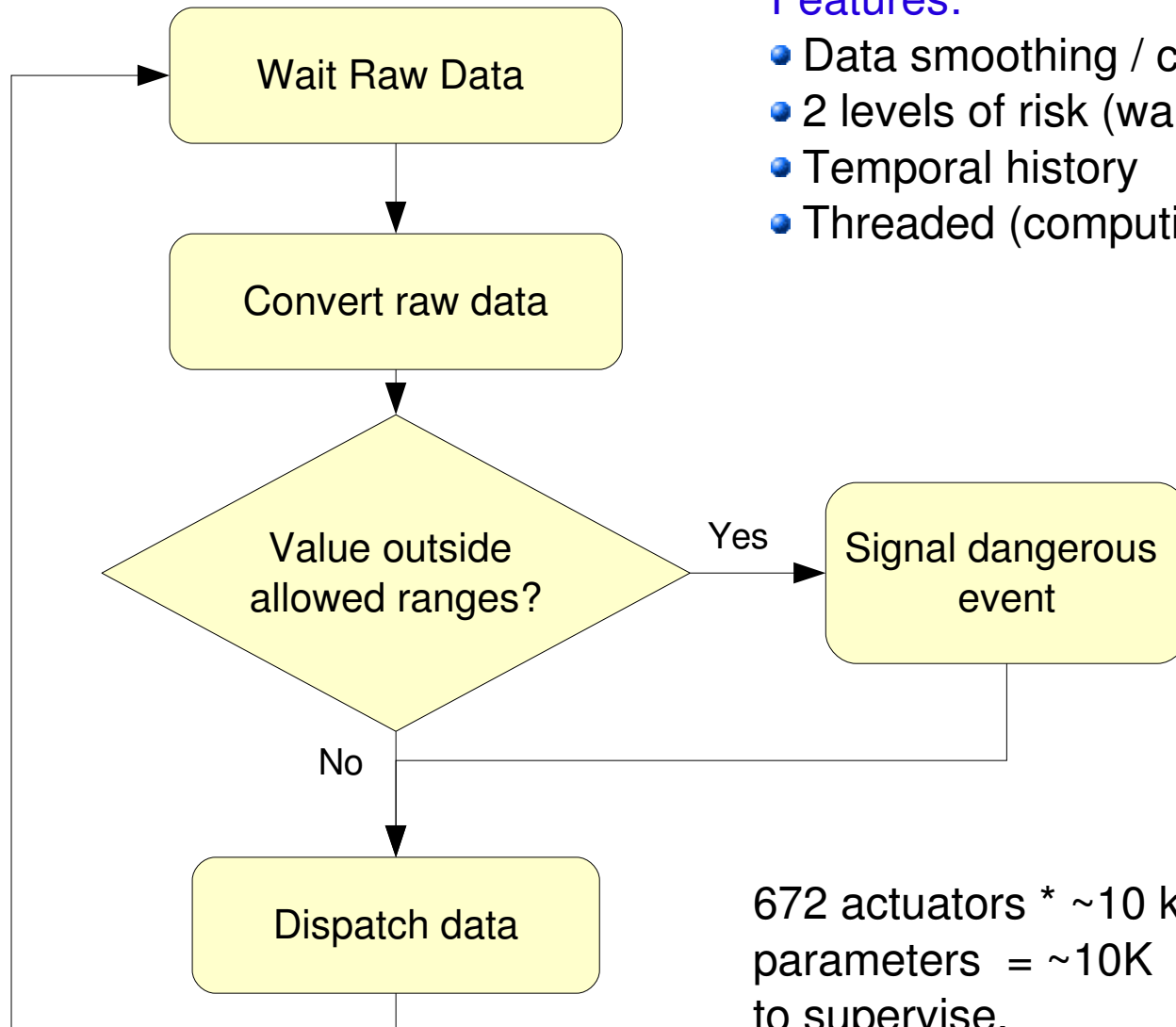
# Diagnostic Application (DiagnApp)

## Features:

- Data smoothing / consecutive allowed faults
- 2 levels of risk (warning / alarm)
- Temporal history
- Threaded (computing shell stress can be long )

## Change behavior **at run-time**:

- enable/disable a variable
- modify warn/alarm ranges
- modify smoothing filters
- configure time-history
- etc...



672 actuators \* ~10 kinds of diagnostic parameters = ~10K diagnostic variables to supervise.

# Derived from DiagnApp

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- *fastdiagn* : monitor of the secondary shell
- *housekeeper* : monitor of the health status of electronics
- *AOdiagnostic* : monitor of the quality of optical loop